Applicant(s)/Patent Under Reexamination Application/Control No. WATANABE ET AL. 09/862,497 Notice of References Cited Art Unit Examiner Page 1 of 1 1752 John S. Chu

U.S. PATENT DOCUMENTS

				U.S. PATENT DOCUMENTS	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification 430/270.1
\dashv		US-6,110,640	08-2000	Kawamura et al.	430/276.1
-	В	US-5,723,253	03-1998	Higashino et al.	430/270.1
_	С	US-6,423,467	07-2002	Kawauchi et al.	
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